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Standard Terminology Relating to Surface Imperfections on Ceramics¹

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1. Scope

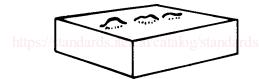
1.1 This terminology describes and illustrates imperfections observed on whitewares and related products. For additional definitions of terms relating to whitewares and related products, refer to Terminology C 242. To observe these defects, examination shall be performed visually, with or without the aid of a dye penetrant, as described in Test Method C 949. Agreement by the manufacturer and the purchaser regarding specific techniques of observation is strongly recommended.

2. Referenced Documents

- 2.1 ASTM Standards:
- C 242 Terminology of Ceramic Whitewares and Related $\mathsf{Products}^2$
- C 949 Test Method for Porosity in Vitreous Whitewares by Dye Penetration²
- E 165 Practice for Liquid Penetrant Inspection Method³

3. Terminology

blemish—strained or discolored area attributable to normal composition or forming, or both. (See also **inclusion**.)



blister—bubble or gaseous inclusion at the surface which if broken could form a pit, pock, or hole.

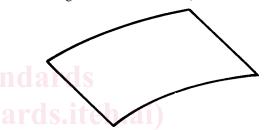


¹ This terminology is under the jurisdiction of ASTM Committee C-21 on Ceramic Whitewares and Related Productsand is the direct responsibility of Subcomittee C21.01 on Nomenclature.

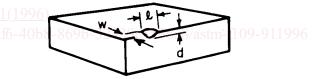
burr—fragment of excess material or foreign particle adhering to the surface.



camber-a single arch of curvature. (See also waviness.)



chip—area along an edge or corner where the material has broken off.



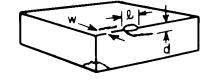
where:

$$w = \text{width}$$

$$l = \text{length, and}$$

$$d = depth.$$

closed chip—fractured area on the edge or corner when the material has not broken off (Syn. *potential chip*).





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² Annual Book of ASTM Standards, Vol 15.02.

³ Annual Book of ASTM Standards, Vol 03.03.